

# MAS 7541A 12-BIT DAC

## APPLICATIONS

- Instrumentation
- Digital Synchro Conversion
- Programmable Amplifiers

## FEATURES

- +/- 1/2 LSB DNL and INL
- No Laser Trimming
- Linearity TC 1.0 pmm/C Max
- 2 kV ESD Protection on Digital Inputs
- TTL/CMOS Compatible
- 3 MSB's Decoded
- Low Sensitivity to Amplifier Offset
- All 4096 Codes Tested
- AD/7541/7541A Replacement
- Available in Die Form
- Low Cost

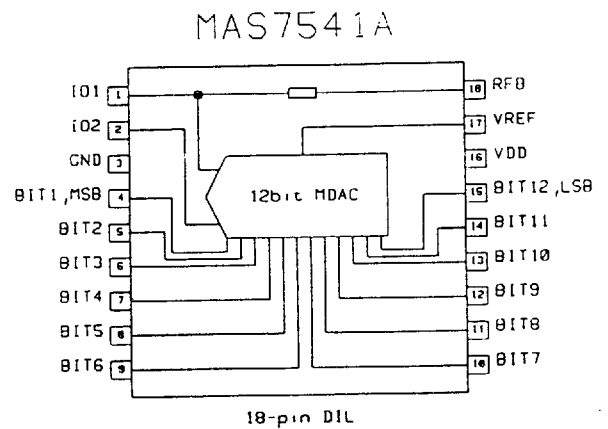
## GENERAL DESCRIPTION

The MAS7541A is a low cost, monolithic CMOS, 12-bit multiplying digital to analog converter (DAC). Its high performance is achieved without laser trimming. This is made possible by the use of highly accurate and stable, low TCR thin film resistor process developed at Micronas and a 3 MSB to 7 decoding design technique. Hidden errors are eliminated by testing all the 4096 different input codes.

The device offers advantages like high stability over time and temperature and low sensitivity to output amplifier offset combined to excellent performance-to-cost ratio. All digital inputs have high ESD protection over 2 kV.

The device is offered in a 18 pin Plastic DIP and Cerdip packages as well as in die form.

## BLOCK DIAGRAM



## ORDERING INFORMATION

Relative Accuracy	Gain Error	Temperature range and package	
Tmin-Tmax	Ta = +25°C	Commercial 0°C to +70°C	Industrial -25°C to +85°C
		Plastic DIP	Cerdip
±1 LSB	±6 LSB	MAS7541A-1CN	MAS7541A-110
±1/2LSB	±3 LSB	MAS7541A-0CN	MAS7541A-010

NOTE: In lieu of cerdip package Micronas reserves the right to ship side braze packaged parts.



# MICRONAS

## Electrical characteristics

VDD = +15V, VREF = 10V, I01 = I02 = GND = 0V, Unipolar unless otherwise specified

Parameter	Symbol	Version	MIN	Ta = +25°C		Tmin-Tmax Limits	Units	Test Conditions/Comments
				TYP	MAX			
<b>STATIC PERFORMANCE</b>								
Resolution	N	All	12			12	Bits	Relative accuracy 11 bits
Integral Nonlinearity <sup>1</sup>	INL	7541A-1 7541A-0			±1 ±1/2	±1 ±1/2	LSB LSB	
Differential Nonlinearity <sup>2</sup>	DNL	7541A-1 7541A-0			±1 ±1/2	±1 ±1/2	LSB LSB	Monotonic to 12 bits Monotonic to 12 bits
Gain Error	Gfse	7541A-1 7541A-0			±6 ±3	±8 ±5	LSB LSB	Measured using internal Rfb DAC register loaded with all 1s
Output Leakage Current at I01 (pin1)	I <sub>lkg</sub>	C I			±5 ±5	±10 ±10	nA nA	All digital inputs = 0V
<b>TEMPERATURE<sup>3</sup> STABILITY</b>								
Gain Error TC	TCGfse	All			±1.0		ppm/°C	
Integral Nonlinearity TC	TCINL	All			±0.1		ppm/°C	
Differential Nonlinearity TC	TCDNL	All			±0.1		ppm/°C	
<b>REFERENCE INPUT</b>								
Input Resistance	Rref	All	7	10	15		kΩ	Input Resistance TC ±150ppm/°C
Voltage Range <sup>3</sup>		All				±25	V	
<b>DIGITAL INPUTS</b>								
Input High Voltage	V <sub>IH</sub>	All	2.4		VDD	2.4	V	Unipolar Coding: Binary Bipolar Coding: Offset Binary
Input Low Voltage	V <sub>IL</sub>	All	-0.3		0.8	0.8	V	
Input Current <sup>4</sup>	I <sub>in</sub>	All			±1	±10	μA	
Input Capacitance <sup>3</sup>	C <sub>in</sub>	All			8	8	pF	
<b>POWER SUPPLY</b>								
Voltage Range	VDD	All	+5	+15	+16		V	Accuracy guaranteed only at +15V All Digital Inputs V <sub>IL</sub> or V <sub>IH</sub> All Digital Inputs 0V or 5V to VDD
Supply Current	IDD	All		2.0	2.5	2.5	mA	
	IDD	All		0.2	0.5	1.0	mA	
<b>TEMPERATURE RANGE</b>								
		C I	0 -25		+70 +85		°C °C	

### NOTES:

1. Integral Nonlinearity is measured as the arithmetic mean value of the magnitudes of the greatest positive deviation and the greatest negative deviation from the theoretical value of any given input combination.
2. Differential Nonlinearity DNL is the deviation of an output step from the theoretical value of 1 LSB for any two adjacent digital input codes.
3. Guaranteed by design but not production tested.
4. Logic inputs are MOS gates. I<sub>in</sub> typical is less than 1 nA at 25°C.



## AC performance characteristics

These characteristics are included for design guidance only and are subject to sample testing only.  
 VDD = +15V, VREF = 10V, IO1 = IO2 = AGND = 0V except where stated. Output Amp is HOS-050.

Parameter	Symbol	Version	Ta = +25°C			Tmin-Tmax Limits	Units	Test Conditions/Comments
			MIN	TYP	MAX			
PROPAGATION DELAY	tPD	All		100			ns	IO1 load R = 100Ω, Cext = 13pF All data inputs 0V to VDD or VDD to 0V From 50% digital input change to 90% of final analog output.
CURRENT SETTLING TIME Full Scale Transition	ts	All		0.6			us	Settling to ±0.01% FSR (strobet). All data inputs 0V to VDD or VDD to 0V
OUTPUT CAPACITANCE CIO1 (pin 16) CIO2 (pin 15) CIO1 (pin 16) CIO2 (pin 15)	Co	All			200 70 70 200	200 70 70 200	PF pF pF pF	Digital inputs VIH Digital inputs VIH Digital inputs VIL Digital inputs VIL
DIGITAL TO ANALOG GLITCH ENERGY	Q	All		1000			nVs	VREF = 0V, DAC Register alternatively loaded with all 0's and 1's
MULTIPLYING FEED THROUGH ERROR AT IO1	FT	All		1.0 0.1			mVpp mVpp	VREF = 20Vpp, f = 10kHz sine wave VREF = 20Vpp, f = 1kHz sine wave
POWER SUPPLY REJECTION Ratio	PSRR	All			±0.02		%/%	VDD = 14-16V

## ABSOLUTE MAXIMUM RATINGS

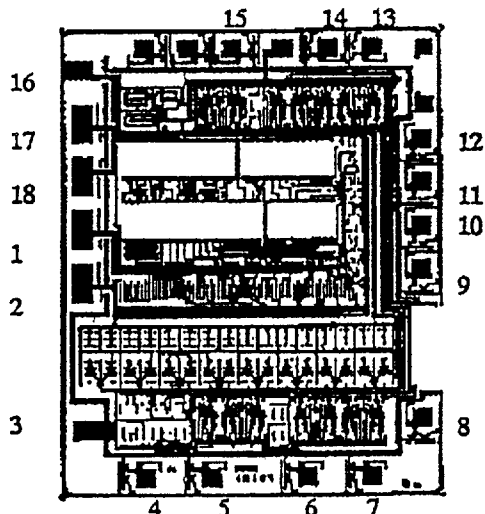
(TA = 25°C unless otherwise noted)

VDD to GND	-0.3, +17V
Digital Input Voltage to GND	-0.3V, VDD + 0.3V
VREF or VRFB to GND	+/-25V
Output Voltage (PIN 1, PIN 2)	-0.3V, VDD + 0.3V
Power Dissipation (Any Package) to +75°C	450 mW
Derates above 75°C by	6 mW/°C
Dice Junction Temperature	+150°C
Storage Temperature	-65°C to +150°C

### CAUTION:

1. Do not apply voltages higher than VDD or less than GND potential on any terminal other than VREF or RFB.
2. The digital inputs are diode clamp protected against ESD damage. However, permanent damage may occur on unprotected units from high-energy electrostatic fields. Keep units in conductive foam at all time until ready to use.
3. Use proper anti-static handling procedures.
4. Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied.

### Dice characteristics



- |                |                  |
|----------------|------------------|
| 1. IO1         | 13. BIT 10       |
| 2. IO2         | 14. BIT 11       |
| 3. GND         | 15. BIT 12 (LSB) |
| 4. BIT 1 (MSB) | 16. VDD          |
| 5. BIT 2       | 17. VREF         |
| 6. BIT 3       | 18. RFB          |
| 7. BIT 4       |                  |
| 8. BIT 5       |                  |
| 9. BIT 6       |                  |
| 10. BIT 7      |                  |
| 11. BIT 8      |                  |
| 12. BIT 9      |                  |

DIE SIZE 87 X 109 mils, 9.500 sq. mils (2.21 x 2.77 mm, 6.12 sq. mm)

### Wafer test limits

TA = +25°C, VDD = +15V, VREF = -10V, IO1 = IO2 = GND = 0V

Parameter	Symbol	Limits	Units	Test Conditions/Comments
<b>STATIC PERFORMANCE</b>				
Integral Nonlinearity	INL	±1	LSB	Note 1. Relative Accuracy 11 bits
Differential Nonlinearity	DNL	±1	LSB	Note 2. Monotonicity 12 bits
Gain Error	Gfse	±6	LSB	Measured using internal Rfb DAC register loaded with all 1s
Output Leakage Current at IO1 (pin 1)	I <sub>lkg</sub>	±10	nA	
<b>REFERENCE INPUT</b>				
Input Resistance	R <sub>ref</sub>	7/15	kΩ	Pad 17, 10 kΩ nominal
<b>DIGITAL INPUTS</b>				
Input High Voltage	V <sub>IH</sub>	2.4	V	
Input Low Voltage	V <sub>IL</sub>	0.8	V	
Input Current	I <sub>in</sub>	±1	μA	V <sub>IN</sub> = 0V or VDD
<b>POWER SUPPLY</b>				
Supply Current	I <sub>DD</sub>	2.5	mA	All Digital Inputs V <sub>IL</sub> or V <sub>IH</sub>
		0.5	mA	All Digital Inputs 0V or 5V to VDD

**NOTES**  
 1. End-point linearity  
 2. Differential Nonlinearity DNL is the deviation of an output step from the theoretical value of 1 LSB for any two adjacent digital input codes.

